

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/598,561 ABE ET AL.	
		Examiner	Art Unit SON DANG	3773 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,935,027 A	06-1990	Yoon, Inbae	606/146
*	B	US-5,037,433 A	08-1991	Wilk et al.	606/139
*	C	US-5,336,231 A	08-1994	Adair, Edwin L.	606/148
*	D	US-5,462,560 A	10-1995	Stevens, Jon A.	606/144
*	E	US-5,665,096 A	09-1997	Yoon, InBae	606/139
*	F	US-5,722,981 A	03-1998	Stevens, Jon A.	606/148
*	G	US-5,782,845 A	07-1998	Shewchuk, Dwight	606/144
*	H	US-5,895,395 A	04-1999	Yeung, Teresa T.	606/144
*	I	US-5,897,563 A	04-1999	Yoon et al.	606/144
*	J	US-5,921,993 A	07-1999	Yoon, InBae	606/140
*	K	US-6,113,610 A	09-2000	Poncet, Philippe	606/139
*	L	US-6,638,286 B1	10-2003	Burbank et al.	606/157
*	M	US-7,320,693 B2	01-2008	Pollack et al.	606/144

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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